

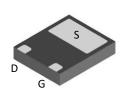
650V GaN Power Transistor (FET)

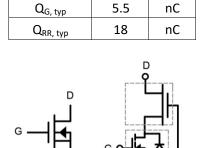
Features

- Easy to use, compatible with standard gate drivers
- Excellent Q_G x R_{DS(on)} figure of merit (FOM)
- Low Q_{RR}, no free-wheeling diode required
- · Low switching loss
- RoHS compliant and Halogen-free

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- High efficiency power supplies
- High efficiency USB PD adapters
- Other consumer electronics





Product Summary

650

720

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 $m\Omega$

Schematic Symbol

 $V_{\text{DSS}} \\$

R_{DS(on), typ}

Cascode Device Structure

Packaging

Part Number	Package	Packaging	Base QTY
RX65T720MS2A	DFN 5 x 6	Tape and Reel	5000

Maximum ratings, at T_C=25 ℃, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T _C =25℃		3.2	Α
I _D	Continuous drain current @T _C =100℃		2.0	Α
	Pulsed drain current @T _C =25℃ (pulse w	idth: 100us)	7.8	Α
I _{DM}	Pulsed drain current @T _C =150℃ (pulse v	width: 100us)	6	Α
V _{DSS}	Drain to source voltage (T₁ = -55℃ to 15	0℃)	650	V
V _{TDSS}	Transient drain to source voltage ^a		800	V
V _{GSS}	Gate to source voltage		±20	V
P _D	Maximum power dissipation @T _C =25℃		14	W
T _C		Case	-55 to 150	°C
T _J	Operating temperature	Junction	-55 to 150	°C
T _S	Storage temperature		-55 to 150	°C
T _{CSOLD}	Soldering peak temperature		260	°C



Thermal Resistance

Symbol	Parameter	Typical	Unit
Rejc	Junction-to-case	8.9	℃/W
Roja	Junction-to-ambient ^b	50	℃/W

Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- b. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm^2 copper area and $70\mu\text{m}$ thickness)



Electrical Parameters, at T₁=25 °C, unless otherwise specified

Symbol	Min	Тур	Max	Unit	Test Conditions
Forward Char	acteristics	I	1		
$V_{DSS\text{-MAX}}$	650	-	-	V	V _{GS} =0V
BV_{DSS}	-	1000	-		V _{GS} =0V, I _{DSS} =250μA
$V_{GS(th)}$	1.1	1.8	2.5	V	V _{DS} =V _{GS} , I _D =500μA
D C	-	720	900	0	V _{GS} =8V, I _D =2A, T _J =25℃
R _{DS(on)} c	-	1440	-	mΩ	V _{GS} =8V, I _D =2A, T _J =150℃
I _{DSS}	-	8	20	μΑ	V _{DS} =700V, V _{GS} =0V, T _J =25℃
IDSS	-	50	-	μΑ	V _{DS} =700V, V _{GS} =0V, T _J =150℃
1	-	-	150	nA	V _{GS} =20V
I _{GSS}	-	-	-150	nA	V _{GS} =-20V
C _{ISS}	-	290	-	pF	
C _{oss}	-	9	-	pF	V _{GS} =0V, V _{DS} =400V, f=1MHz
C_{RSS}	-	0.5	-	pF	
C _{O(er)}	-	13.2	-	pF	
$C_{O(tr)}$	-	47	-	pF	V _{GS} =0V, V _{DS} =0 - 400V
Q _{oss}	-	18	-	nC	
Q_{G}	-	5.5	-		
Q_{GS}	-	1.2	-	nC	V_{DS} =400V, V_{GS} =0 - 8V, I_{D} =2A
Q_{GD}	-	2	-		
t _{D(on)}	-	18	-		
t _R	-	12	-	nc	V 400V V 0 43V L 3.54 B 47O
$t_{D(off)}$	-	60	-	ns	V_{DS} =400V, V_{GS} =0 - 12V, I_{D} =2.5A, R_{G} =47 Ω
t _F	-	12	-		
Reverse Chara	acteristics		1	il.	
	-	1.4	-		V _{GS} =0V, I _S =1A, T _J =25℃
V_{SD}	-	2	-	V	V _{GS} =0V, I _S =2A, T _J =25℃
	-	3.1	-	- V _{GS} =0V, I _S =2A, T _J =150℃	
t _{RR}	-	13	-	ns	
Q_{RR}	_	18	_	nC	$I_S=2A$, $V_{GS}=0V$, $d_i/d_t=1000A/us$, $V_{DD}=400V$

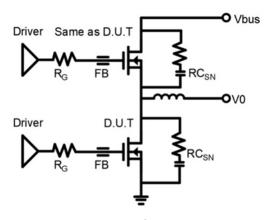
Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



Circuit Implementation

(1) Mostly used in half bridge and full bridge topology



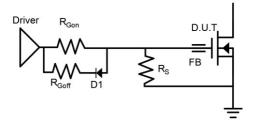
Recommended Half-bridge Circuit

Recommended gate drive: (0 V, 8 V) with $R_{G(tot)} = 40 \Omega$, where $R_{G(tot)} = R_G + R_{driver}$

Gate Ferrite Bead (FB)	Gate Resistance (R _G)	RC Snubber (RC _{SN})
MPZ1608S471ATA00	33 Ω	69 pF + 15 Ω

Notes:

- d. RC_{SN} should be placed as close as possible to the drain pin
- e. The layout and wiring of the drive circuit should be as short as possible
- (2) Mostly used in flyback, forward and push-pull converters



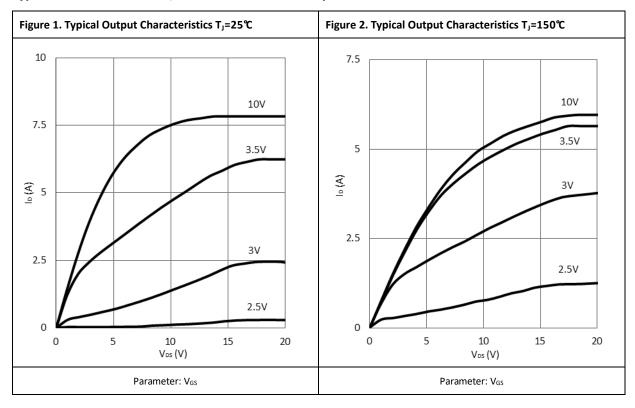
Recommended Single Ended Drive Circuit

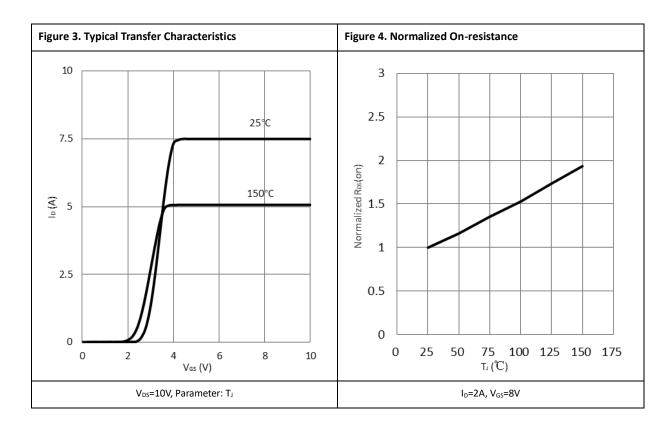
Recommended gate drive: (0 V, 12 V) with R_{Gon} = 300 - 500 Ω , R_{Goff} =10 Ω

Gate Ferrite Bead(FB)	Gate Source Resistance(R _s)	Gate Diode (D1)
300 - 600 Ω@100MHz	10 kΩ	1N4148

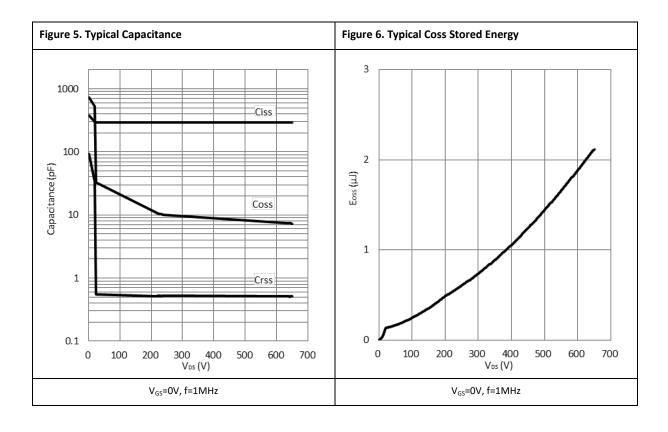


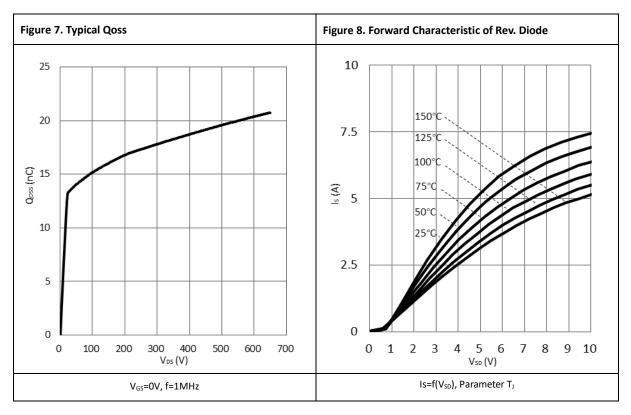
Typical Characteristics, at $T_C=25~^{\circ}C$, unless otherwise specified



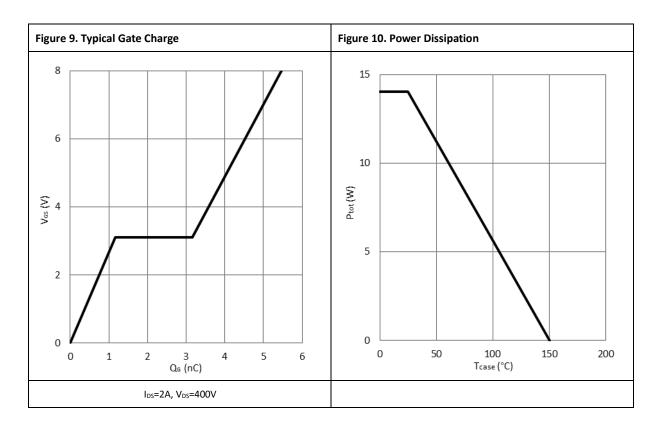


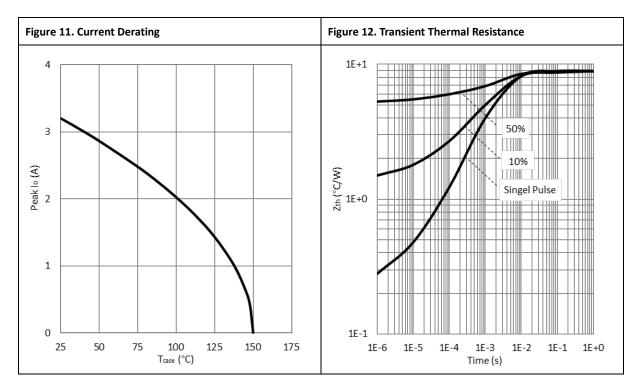




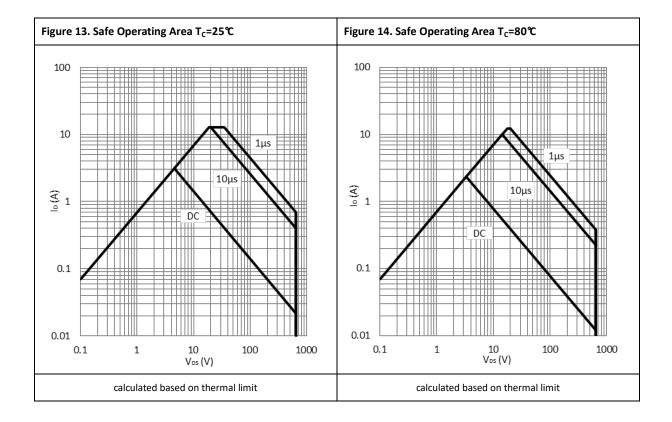






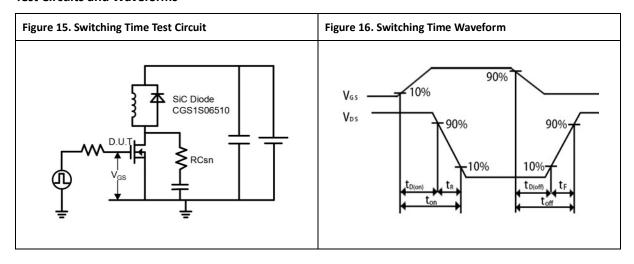


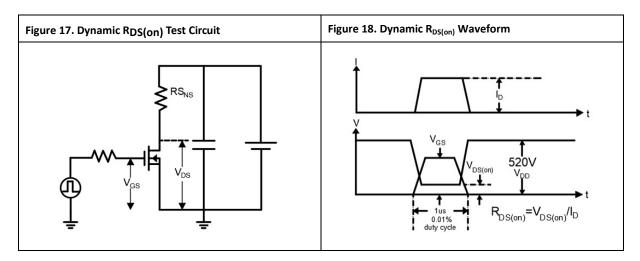


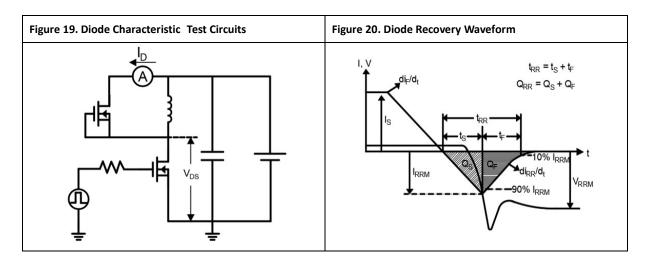




Test Circuits and Waveforms









Design Considerations

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

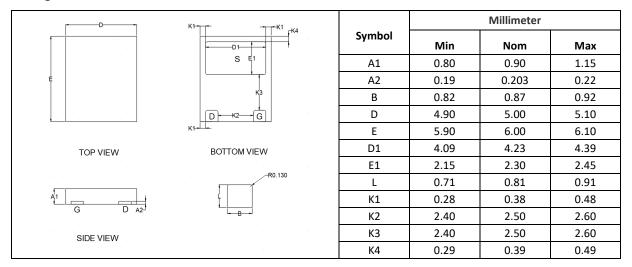
When Evaluating Runxin Micro's GaN Devices:

DO	DO NOT
Make sure the traces are as short as possible for both drive and power loops to minimize parasitic inductance	Using Runxin Micro's devices in GDS board layouts
Use the test tool with the shortest inductive loop, and make sure test points should be placed close enough	Use differential mode probe or probe ground clip with long wires
Minimize the lead length of DFN 8*8mm packages when installing them to PCB	Use long traces in drive circuit, or long lead length of the devices





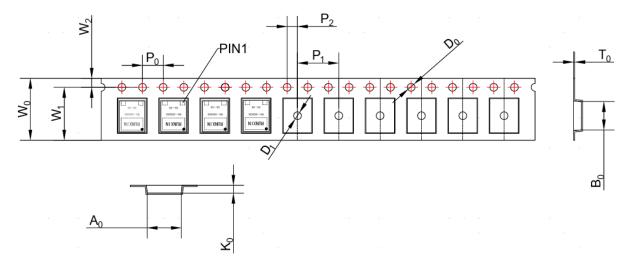
Package Outline

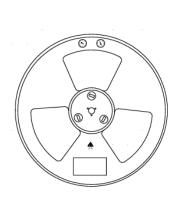


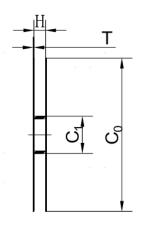


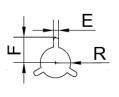
Tape and Reel Information

Dimensions are shown in millimeters









Tape Dimension					
W_0	12+0.3-0.1	P_0	4±0.1	A_0	5.4±0.1
W_1	10.25±0.1	P ₁	8±0.1	B ₀	6.4±0.1
W ₂	1.75±0.1	P ₂	2±0.1	D_1	1.5±0.25
K ₀	1.4±0.1	D_0	1.5±0.1	T ₀	0.30±0.05

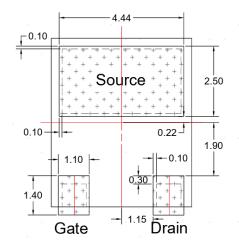
Reel Dimension				
Н	14±0.1	F	10.5±0.1	
Т	2±0.2	E	2.8±0.1	
C_0	330±3	R	6.5±0.1	
C_1	100±1			

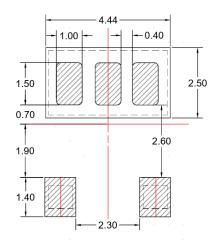




Recommended PCB Layout & Stencil apertures

Dimensions are shown in millimeters





Chip electrodes

PCB layout

Stei

Stencil aperture



Revision History

Version	Date	Change(s)
1.0	2023/08/28	Release formal datasheet
1.1	2024/03/14	Revise I _D , output, transfer, Capacitance, Is, Qg, Qrr, Qoss, Figure 1, 2, 3, 8, 9, 12, 13, 14

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.